



National Institute of Standards & Technology

# Certificate of Analysis

## Standard Reference Material<sup>®</sup> 1134

### Low-Alloy High-Silicon Steel (disk form)

This Standard Reference Material (SRM) is a low-alloy steel issued in the annealed condition and containing a high amount of silicon. SRM 1134 is intended for use in the evaluation and calibration of chemical and instrumental methods of analysis. A unit of SRM 1134 consists of a disk approximately 31 mm diameter and 19 mm thick.

**Certified Mass Fraction Values:** The measurand is the certified value for each constituent in SRM 1134. Certified values for 10 constituents are reported in Table 1 as mass fractions [1]. Value assignment categories are based on the definitions of terms and modes used at NIST for chemical reference materials [2]. A NIST certified value is a value for which NIST has the highest confidence in its accuracy, in that all known or suspected sources of bias have been investigated or taken into account. A certified value is the present best estimate of the true value based on the results of analyses performed at NIST and collaborating laboratories. Metrological traceability is to the derived SI unit for mass fraction (expressed as a percent).

**Reference Mass Fraction Values:** The measurand is the reference value for aluminum reported in Table 2. A reference value is a non-certified value that is the best estimate of the true value; however, the value does not meet the NIST criteria for certification and is provided with the associated uncertainty that may not include all sources of uncertainty [2]. Metrological traceability is to the derived SI unit for mass fraction (expressed as a percent).

**Information Mass Fraction Values:** Information values for six constituents are reported in Table 3. An information value is considered to be a value that will be of interest to the SRM user, but insufficient information is available to assess the uncertainty associated with the value. Information values cannot be used to establish metrological traceability.

**Expiration of Certification:** The certification of **SRM 1134** is valid indefinitely, within the uncertainty specified, provided the SRM is handled and stored in accordance with the instructions given in this certificate (see “Instructions for Use”). Accordingly, periodic recalibration or recertification of this SRM is not required. The certification is nullified if the SRM is damaged, contaminated or otherwise modified.

**Maintenance of SRM Certification:** NIST will monitor this material over the period of its certification. If substantive technical changes occur that affect the certification before the expiration of this certificate, NIST will notify the purchaser. Registration (see attached sheet, or register online) will facilitate notification.

Coordination of the original certification of SRM 1134 in 1970 was performed by O. Menis of the former Office of Standard Reference Materials of the National Bureau of Standards and J.I. Schultz, ASTM Research Associate. Coordination of the reevaluation of SRM 1134 was performed by J.R. Sieber of the NIST Chemical Sciences Division.

Statistical consultation for the value assignment of SRM 1134 was provided by J.H. Yen of the NIST Statistical Engineering Division.

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Certificate Issue Date: 19 September 2017  
*Certificate Revision History on Last Page*

Measurements for value assignment of SRM 1134 were performed at NIST by J.R. Baldwin, D.D. Bendigo, E.R. Deardorff, E.L. Garner, A.F. Marlow, T.J. Murphy, T.C. Rains, T.A. Rush, J.R. Sieber, B.A. Thompson, and S.A. Wicks of the NIST Chemical Sciences Division. Homogeneity testing at NIST was performed by J.R. Baldwin, D.M. Bouchette, R.F. Brady, J. McKay, S.D. Rasberry, J.L. Webber, and S.A. Wicks. Analyses were also performed by M. Dannis and R.L. LeRoy, Armco Steel Corporation, Middletown, OH, and L.M. Melnick, W.R. Bandi, H.S. Karp, J.L. Lutz, R.W. Lewis, J.B. Ferons, and H.M. Lewis, United States Steel Corporation, Monroeville, PA

Support aspects involved in the issuance of this SRM were coordinated through the NIST Office of Reference Materials.

## INSTRUCTIONS FOR USE

The test surface is the side opposite from the labeled surface, which includes the SRM number. The entire thickness of the unit is certified. However, the user is cautioned not to measure disks less than 2 mm thick when using X-ray fluorescence spectrometry. Each packaged disk has been prepared by finishing the test surface using a milling machine. The user must determine the correct surface preparation procedure for each analytical technique. The user is cautioned to use care when either resurfacing the disk or performing additional polishing as these processes may contaminate the surface. It was found by NIST that abrasive paper must be changed frequently during surface grinding. Used paper loses its ability to remove contaminants from the surface of the steel. When not in use, the material should be stored in its original container in a cool, dry location. This material was tested using both the solid disks and chips prepared from the disks. The certified values are considered to be representative of the overall average composition of the material.

## PREPARATION AND ANALYSIS<sup>(1)</sup>

The material for SRM 1134 was prepared by the Armco Steel Corporation (Middletown, Ohio). A single ingot was pressed to a slab after having one dimension of the cross section four times that of the other dimension. After cropping top and bottom, the slab was cut lengthwise and the center section, corresponding to about one-fourth of the original ingot, was discarded. Slab sections were hot rolled to oversized rods and centerless ground to final rod size of 31.8 mm diameter. Some rods were sliced to prepare SRM 1134.

Homogeneity testing performed at NIST included metallographic studies, optical emission spectrometry, X-ray fluorescence spectrometry, and chemical analysis. The testing revealed the material to be homogeneous.

**Certified Value Assignment:** Each certified value is the mean of the method means available for that analyte. A method mean may combine the results of closely related methods. The uncertainty provided with each value is an expanded uncertainty about the mean to cover the measurand with approximately 95 % confidence. The expanded uncertainty is calculated as  $U = ku_c$ , where  $u_c$  incorporates both the observed differences among the results from the methods and their respective uncertainties, consistent with the ISO Guide and Supplement 1, and  $k$  is a coverage factor corresponding to approximately 95 % confidence for each analyte [3–5]. Test methods are shown in Table 4.

Table 1. Certified Mass Fraction Values for SRM 1134

Element	Mass Fraction (%)	Expansion Factor, $k$
C	0.0261 ± 0.0030	3.2
Cr	0.0198 ± 0.0017	2.0
Cu	0.0707 ± 0.0011	2.0
Mn	0.2751 ± 0.0037	2.0
Mo	0.0087 ± 0.0007	2.0
Ni	0.0375 ± 0.0011	2.0
P	0.0276 ± 0.0012	2.8
S	0.0095 ± 0.0022	2.8
Si	2.889 ± 0.018	2.0
Sn	0.0034 ± 0.0004	2.0

**Reference Value Assignment:** The reference value is the unweighted mean of three method means. The uncertainty of the reference value is expressed as an expanded uncertainty,  $U$ , and is calculated according to the method described

<sup>(1)</sup>Certain commercial equipment, instrumentation, or materials are identified in this certificate to specify adequately the experimental procedure. Such identification does not imply recommendation or endorsement by NIST, nor does it imply that the materials or equipment identified are necessarily the best available for the purpose.

in the ISO Guide [3]. The expanded uncertainty is calculated as  $U = ku_c$ , where  $u_c$  is intended to represent, at the level of one standard deviation, the combined effect of estimated between-method and within-method components of uncertainty [3]. Test methods are shown in Table 4.

Table 2. Reference Mass Fraction Value for SRM 1134

Element	Mass Fraction (%)	Expansion Factor, $k$
Al	0.329 ± 0.007	4.3

Table 3. Information Mass Fraction Values for SRM 1134

Element	Mass Fraction (%)
As	0.003
Co	0.007
Fe	95.8
Sb	0.0009
Ti	0.004
V	0.0005
Zr	0.001

Table 4. Analytical Methods for SRM 1134

Element	Method(s) <sup>(a)</sup>	Element	Method(s) <sup>(a)</sup>
Al	1, 2, 3	Ni	4, 16
As	4	P	4, 17, 18
C	5, 6	S	4, 19
Co	4	Sb	4
Cr	4, 7, 8, 9	Si	4, 20, 21
Cu	4, 9, 10, 11	Sn	4, 22, 23
Fe	4	Ti	4
Mn	4, 12, 13, 14	V	4
Mo	4, 7, 15	Zr	4

<sup>(a)</sup>Key to Methods in Table 4:

1. Flame emission spectrometry
2. Precipitation as phosphate, ignition and weighing as  $AlPO_4$
3. Ether, Hg cathode, cupferron, chrome-azurol-S spectrometric method
4. X-ray fluorescence spectrometry
5. Direct combustion followed by gravimetric determination
6. Direct combustion followed by thermal conductivity detection
7. Neutron activation analysis
8. Oxidation with peroxydisulfate followed by titration with  $KMnO_4$
9. Diphenylcarbazide spectrometric method
10. Diethyldithiocarbamate spectrometric method
11. Isotope dilution mass spectrometry
12. Peroxydisulfate arsenite method
13. Potentiometric titration
14. Periodate spectrometric method
15. Sulfide-iodine method [6]
16. Photometric method
17. Spectrophotometric molybdenum-blue method
18. Ammonium phosphomolybdate extraction with isobutyl alcohol, reduced to molybdenum blue, and determined spectrometrically
19. Combustion and absorption in starch-iodide solution followed by titration with  $KIO_3$  solution
20. Gravimetric determination after  $HClO_4$  dehydration
21. Double dehydration with intervening filtration
22. Polarographic determination
23. Thiocyanate-ethylene glycol molybdenum complex extracted with monobutyl ether and determined spectrophotometrically

## REFERENCES

- [1] Thompson, A.; Taylor, B.N.; *Guide for the Use of the International System of Units (SI)*; NIST Special Publication 811; U.S. Government Printing Office: Washington, DC (2008); available at <http://www.nist.gov/pml/pubs/sp811/index.cfm> (accessed Sep 2017).
- [2] May, W.; Parris, R.; Beck, C.; Fassett, J.; Greenberg, R.; Guenther, F.; Kramer, G.; Wise, S.; Gills, T.; Colbert, J.; Gettings, R.; MacDonald, B.; *Definitions of Terms and Modes Used at NIST for Value-Assignment of Reference Materials for Chemical Measurements*; NIST Special Publication 260-136; U.S. Government Printing Office: Gaithersburg, MD (2000); available at <http://www.nist.gov/srm/publications.cfm> (accessed Sep 2017).
- [3] JCGM 100:2008; *Evaluation of Measurement Data — Guide to the Expression of Uncertainty in Measurement (ISO GUM 1995 with Minor Corrections)*; Joint Committee for Guides in Metrology (JCGM) (2008); available at [http://www.bipm.org/utis/common/documents/jcgm/JCGM\\_100\\_2008\\_E.pdf](http://www.bipm.org/utis/common/documents/jcgm/JCGM_100_2008_E.pdf) (accessed Sep 2017); see also Taylor, B.N.; Kuyatt, C.E.; *Guidelines for Evaluating and Expressing the Uncertainty of NIST Measurement Results*; NIST Technical Note 1297; U.S. Government Printing Office: Washington, DC (1994); available at <http://www.nist.gov/pml/pubs/index.cfm> (accessed Sep 2017).
- [4] JCGM 101:2008; *Evaluation of Measurement Data – Supplement 1 to the Guide to the Expression of Uncertainty in Measurement – Propagation of Distributions Using a Monte Carlo Method*; Joint Committee for Guides in Metrology (JCGM) (2008); available at [http://www.bipm.org/utis/common/documents/jcgm/JCGM\\_101\\_2008\\_E.pdf](http://www.bipm.org/utis/common/documents/jcgm/JCGM_101_2008_E.pdf) (accessed Dec 2012).
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- [6] J. Res. Nat. Bur. Stand., Vol. 8, p. 309 (1932) RP415.

<b>Certificate Revision History:</b> <b>19 September 2017</b> (Title change; editorial changes); <b>03 December 2012</b> (Update of unit size, editorial changes) <b>14 April 2011</b> (This revision updates the certificate to current NIST standards and reports revised constituents and values); <b>30 April 1970</b> (original certificate date).
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*Users of this SRM should ensure that the Certificate of Analysis in their possession is current. This can be accomplished by contacting the SRM Program: telephone (301) 975-2200; fax (301) 948-3730; e-mail [srminfo@nist.gov](mailto:srminfo@nist.gov); or via the Internet at <http://www.nist.gov/srm>.*